Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/016,434	TANIGAWA ET AL.	
Examiner	Art Unit	
Annan Q. Shang	2623	

SEARCHED			
Class	Subclass	Date	Examiner
725	37-61	2/8/2006	A.S

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH	STRATEGY	")
,	DATE	EXMR
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